Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,674	PARMAR ET AL.	
Examiner	Art Unit	
DANH C. LE	2617	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Name Search	414/06	DCL		
Inventor Name Search (check for double patenting) EAST Search				
(USP, USPUB)				